

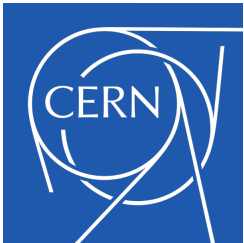
Performance and radiation hardness of Tower 180 nm MALTA monolithic pixel sensors

Martin Gazi (Oxford)

P. Allport (Birmingham), I. Asensi Tortajada (CERN), D.V. Berlea (DESY), D. Bortoletto (Oxford), C. Buttar (Glasgow), E. Charbon (EPFL), F. Dachs (CERN), V. Dao (CERN), D. Dobrijevic (CERN, Zagreb), L. Flores Sanz de Acedo (CERN, Glasgow), M. Gazi (Oxford), L. Gonella (Birmingham), V. Gonzalez (Valencia), G. Gustavino (CERN), M. LeBlanc (CERN), H. Pernegger (CERN), F. Piro (CERN, EPFL), P. Riedler (CERN), H. Sandaker (Oslo), A. Sharma (CERN), W. Snoeys (CERN), C.A. Solans Sanchez (CERN), T. Suligoj (Zagreb), M. van Rijnbach (CERN, Oslo), M. Vazquez Nunez (CERN, Valencia), J. Weick (CERN, Darmstadt), S. Worm (DESY), A.M. Zoubir (Darmstadt)

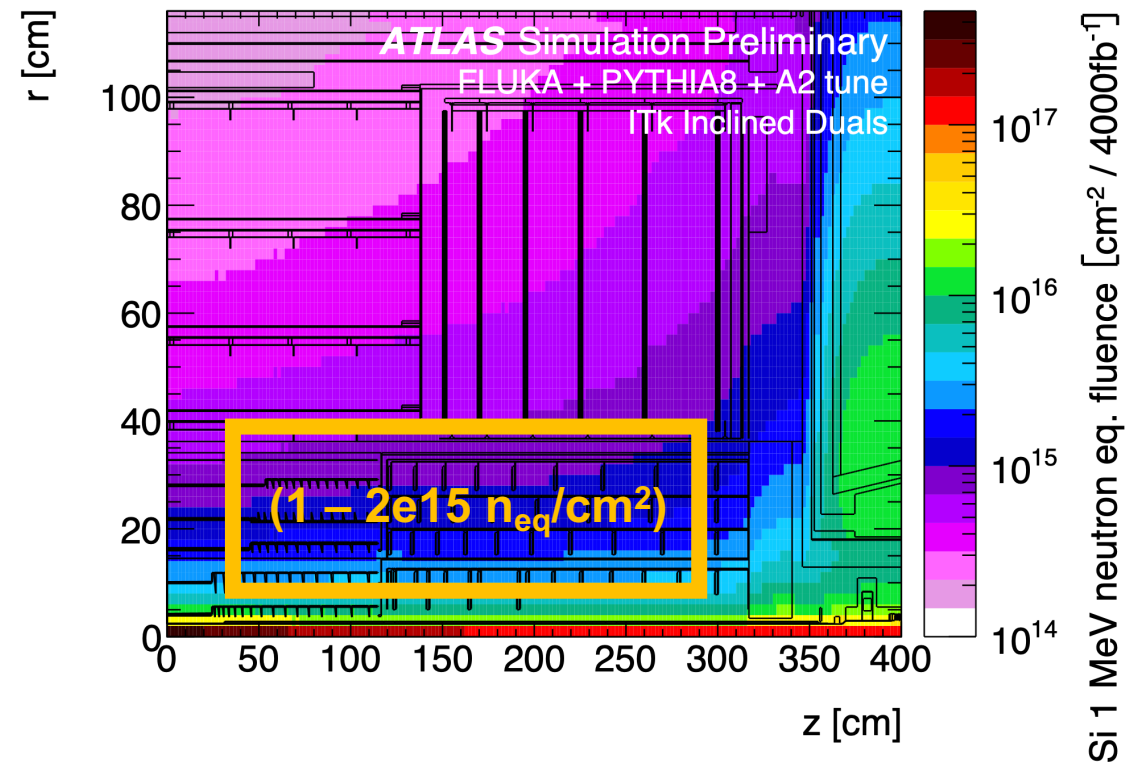
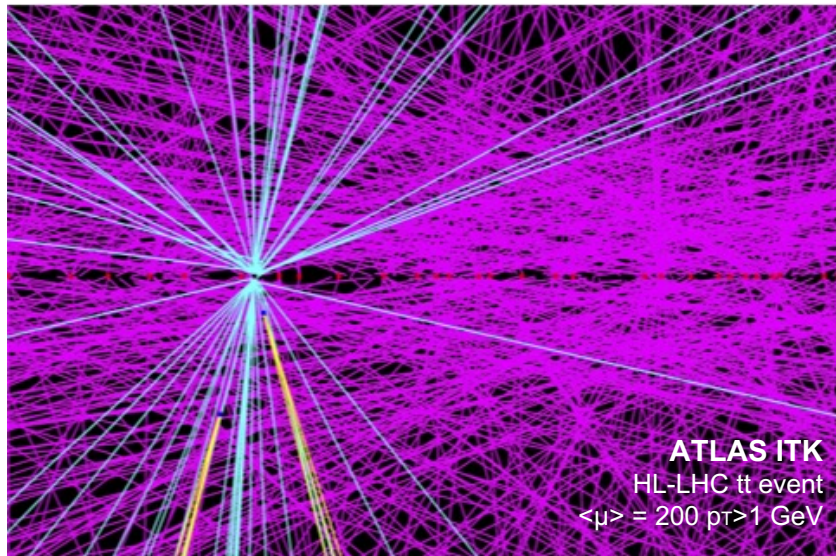
TREDI 2023 - 18th Trento Workshop on Advanced Silicon Radiation Detectors

01 March 2023

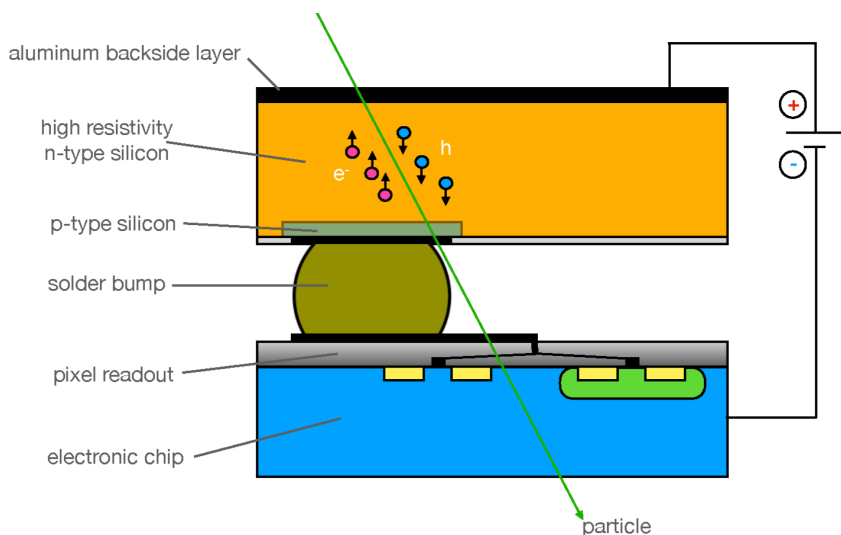


Motivation for Monolithic pixel detectors

- Next generation of high-energy physics hadron experiments demanding on detectors
 - High radiation tolerance
 - High granularity (2 MHz/mm² hit rates)
 - Low material budget (cooling, power consumption)
 - Good timing response (<25 ns)
 - Large surface area -> affordable?

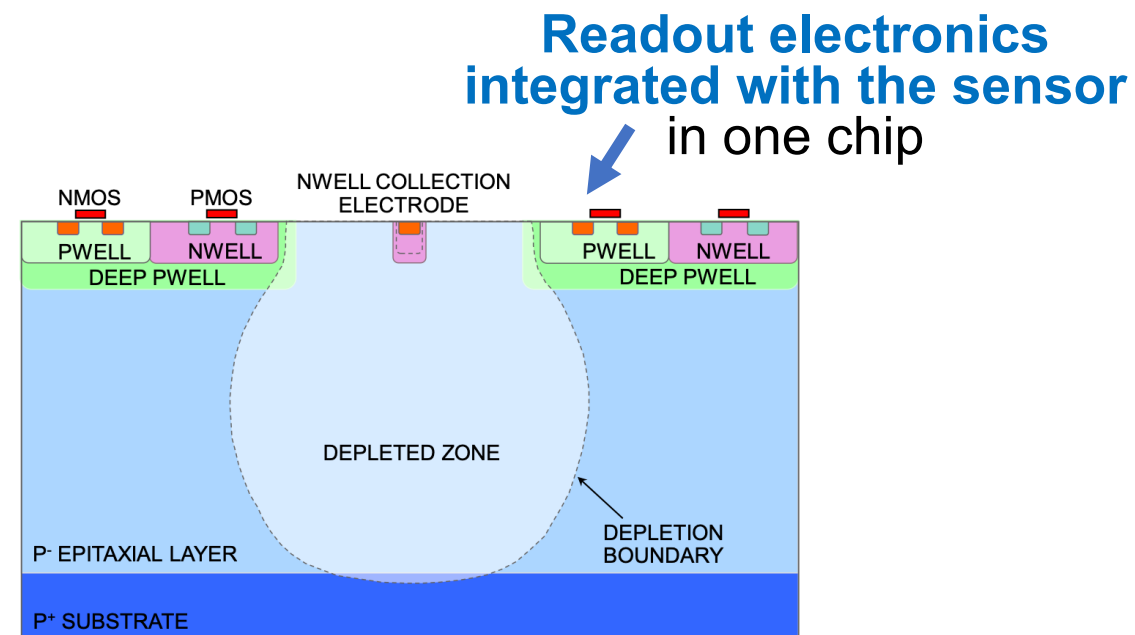


Monolithic Active Pixel Sensors (MAPS)



Hybrid detectors

- ASIC bump-bonded to sensor
- Expensive bump bonding
- Well-understood radiation tolerance



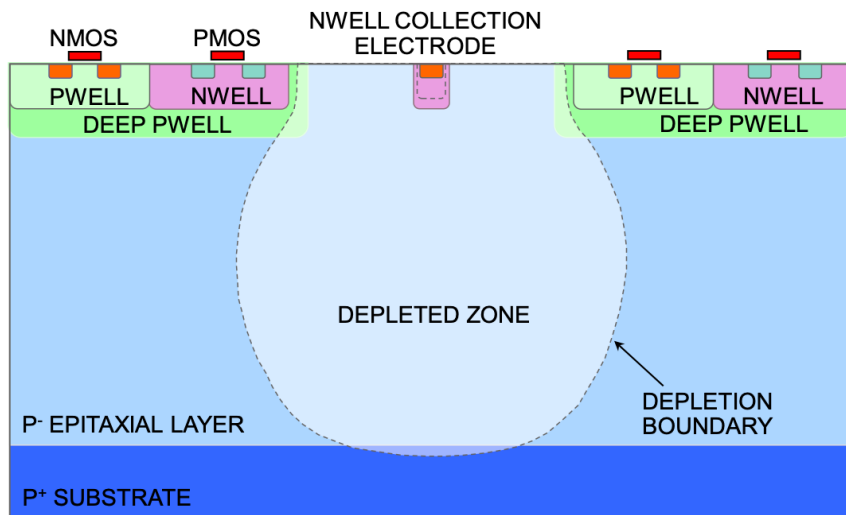
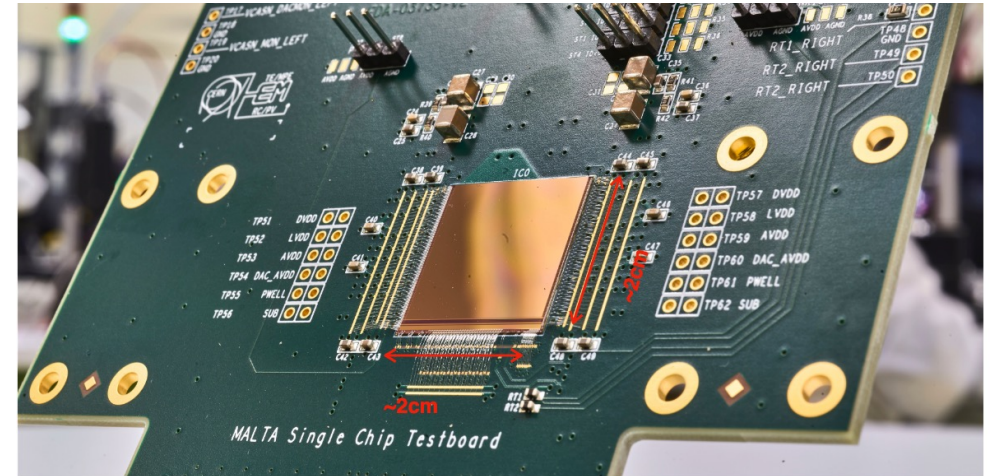
Monolithic sensors

- One chip (readout + sensor)
- No bump bonding, less power needs
- **Radiation tolerance needs to be studied**

Focus of this talk

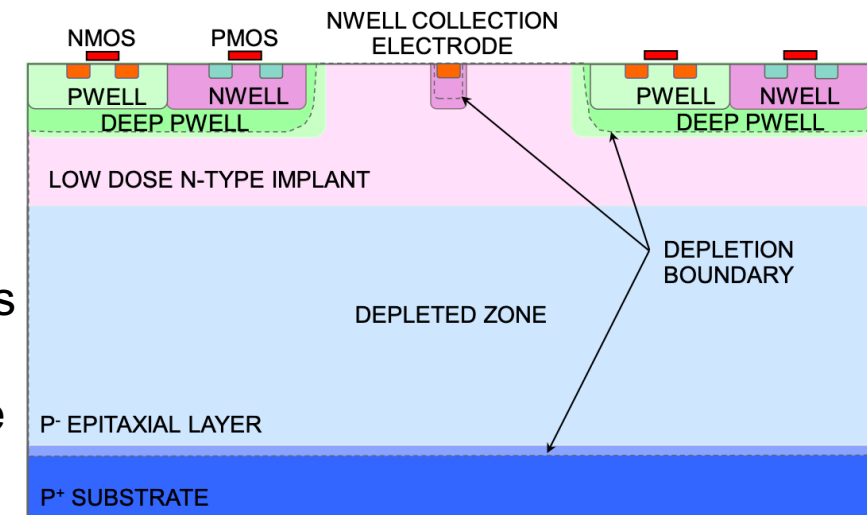
Tower MALTA

- ❑ Full-scale demonstrator to target specifications for ATLAS ITk outer layer
- ❑ 180 nm Tower Semiconductor (formerly TowerJazz) CMOS imaging technology process
 - ❑ Utilising Tower modified process



Modified process

- ❑ Low-dose n-type implant under p-well fully depleted pixel area
- ❑ Charge carriers pushed towards the collection electrode
- ❑ Reduces charge carrier capture probability

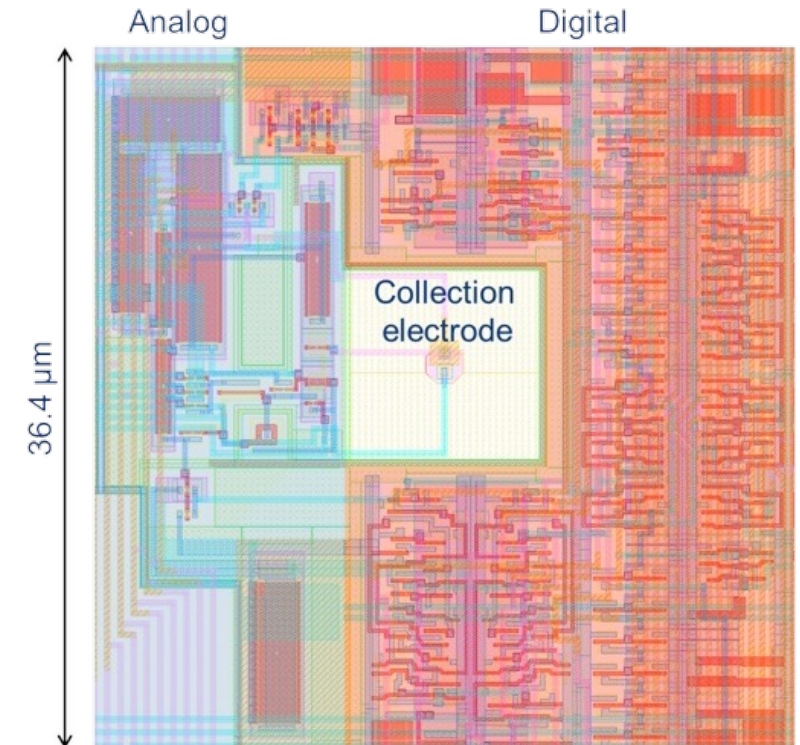


H. Pernegger, et al, 2017 JINST 12 P06008

MALTA pixel and readout

- ❑ MALTA pixel pitch: 36.4 x 36.4 μm ATLAS: 50x250/400 μm^2
- ❑ Collection electrode: 3 x 3 μm , small capacitance (5 fF)
- ❑ Low power usage: 1 μW per pixel ATLAS: ~ 150 $\mu\text{W}/\text{pixel}$
(<70 mW/cm^2 analog power)
- ❑ Asynchronous read-out \rightarrow no distributed clock
- ❑ Readout: **clock-less, asynchronous**
 - ❑ Parallel output signal transmission
 - ❑ Theoretical hit rate >100 MHz
 - ❑ Oversampling used for time-stamping
 - ❑ No time-over-threshold

I. Berdalovic et al, JINST, 2018, 13, C01023

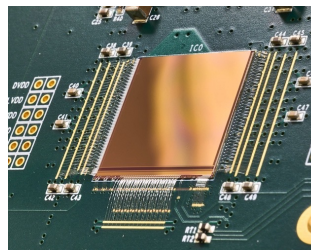


The evolution of MALTA

MALTA1

Jan
2018

Large demonstrator
2 x 2 cm²

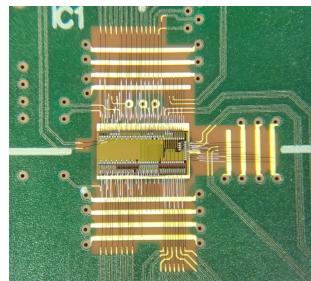


- Sensor functional, slow control issues
- Poor lateral field after irradiation

Mini-MALTA

Jan
2019

Small demonstrator
1.7 x 0.5 cm²

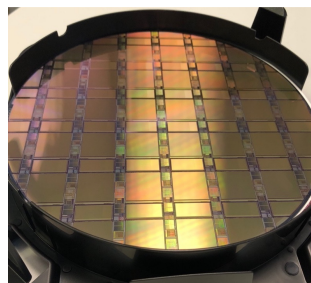


- Introduction of sensor modification
- Radiation hard, full efficiency at 1e15 n_{eq}/cm²

MALTA C

Aug
2019

Epitaxial (Epi) and
Czochralski (Cz)
substrates

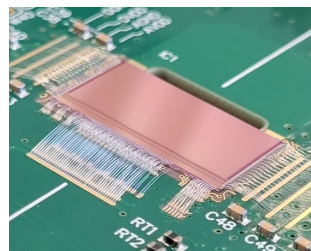


- Significant improvement of Cz substrate efficiency at high voltage after irradiation

MALTA2

Jan
2021

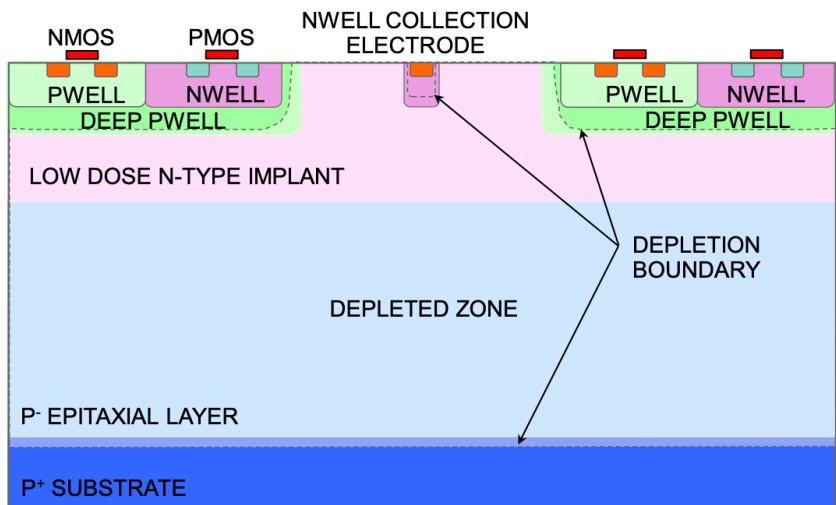
Smaller matrix
2 x 1 cm²



- Improved chip synchronisation
- Improved time resolution
- Improved noise performance

Additional process modifications

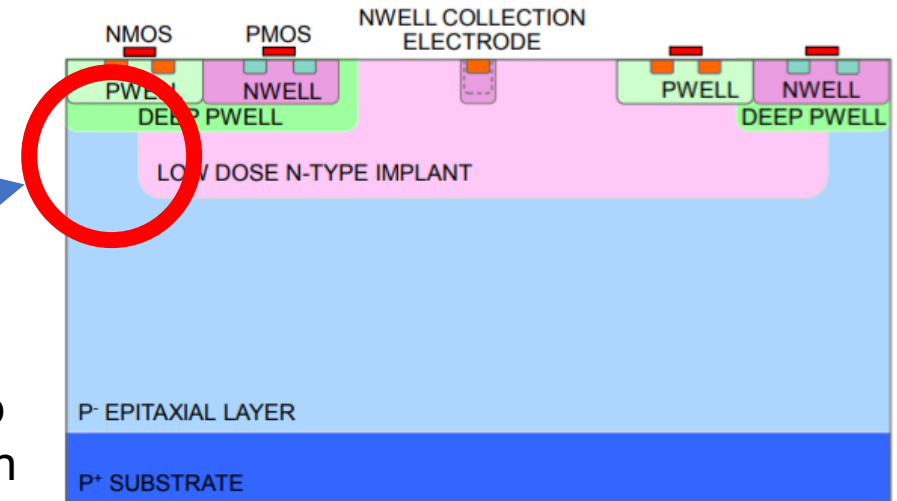
“Standard” modified process



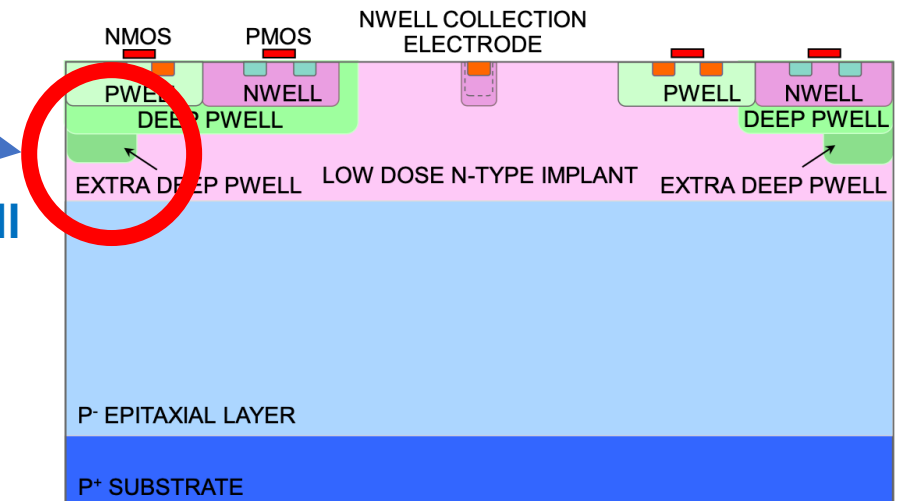
- Lateral electric field not sufficient to push the deposited charge towards the small central electrode.
- Efficiency decreases in pixel corners
 - Effect amplified by radiation damage

N-layer gap (NGAP)

Process modifications to improve charge collection in the pixel edges



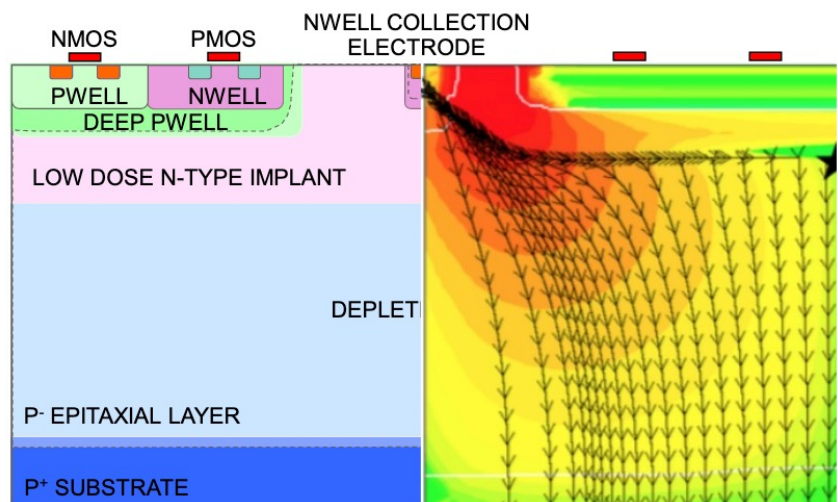
Extra Deep P-Well (XDPW)



M. Munker, JINST 14 (2019) C05013

Additional process modifications

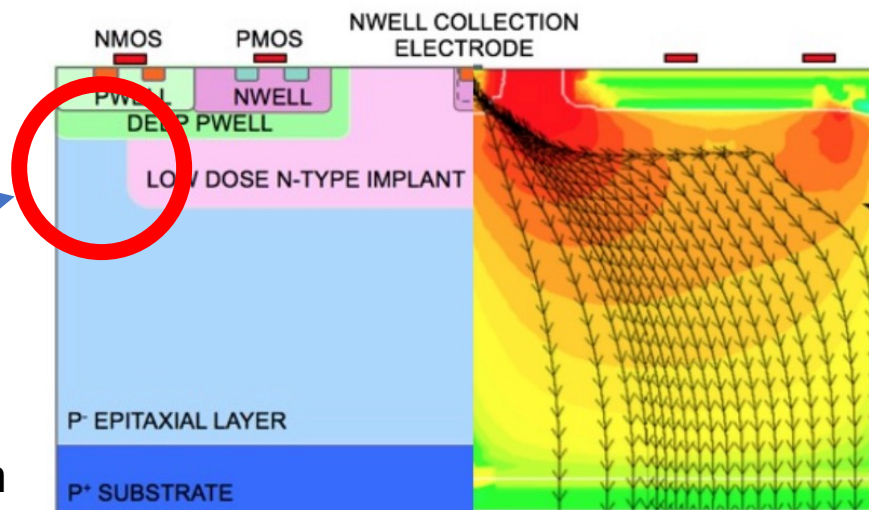
“Standard” modified process



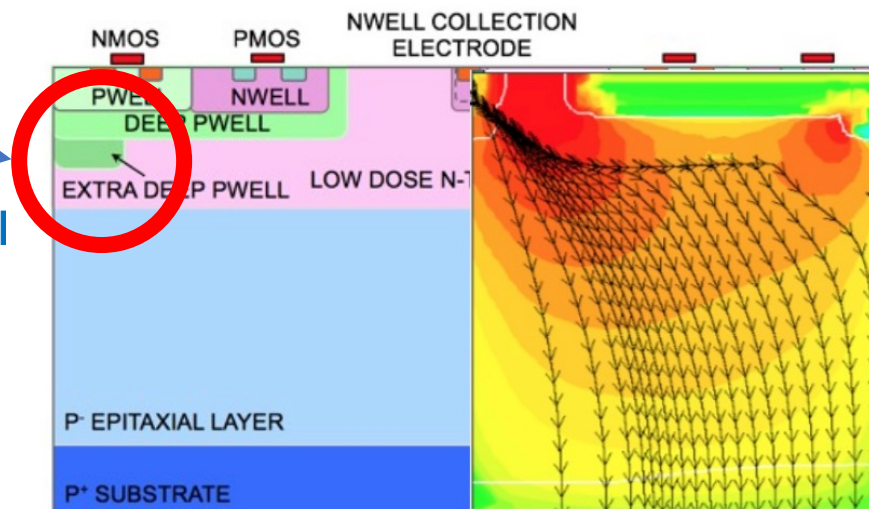
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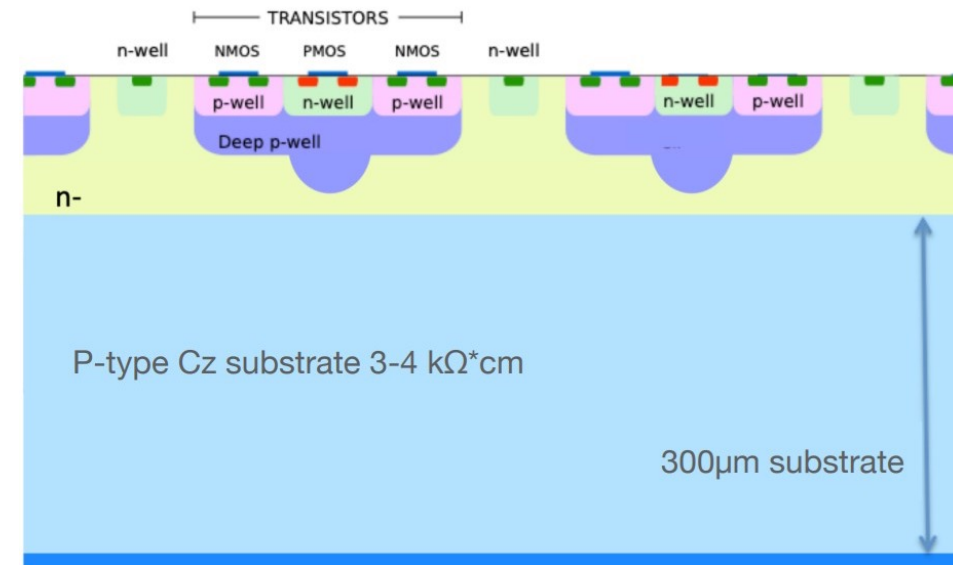
Extra Deep P-Well (XDPW)



M. Munker, JINST 14 (2019) C05013

Sensor substrate – Epitaxial and Czochralski

- ❑ Variation introduced in MALTA C – also investigated with MALTA2
- ❑ Epitaxial silicon substrate limited to 30 μm
 - ❑ High resistivity
- ❑ Czochralski (Cz) substrate (3-4 $\text{k}\Omega\text{ cm}$)
 - ❑ used for full detection volume (100 – 300 μm)
 - ❑ depletion proportional $\sqrt{V_{\text{SUB}}}$
 - ❑ results in larger cluster size
 - ❑ **enhanced radiation resistance**

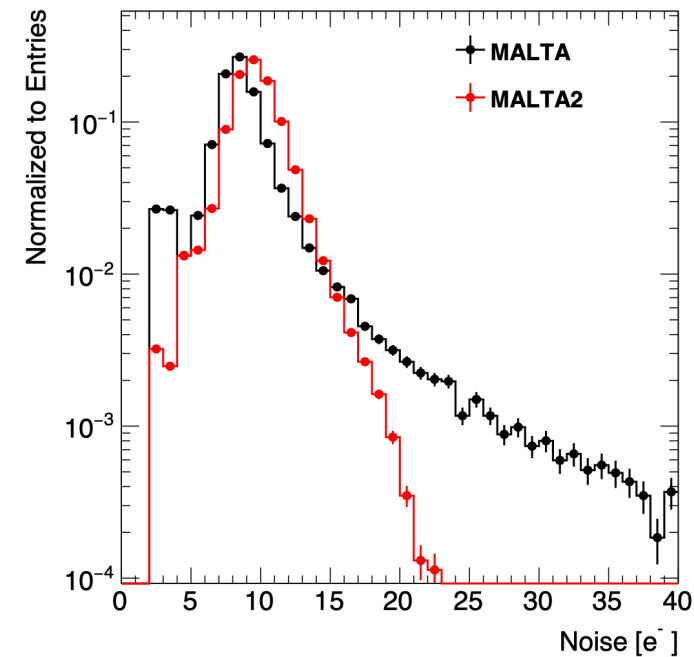
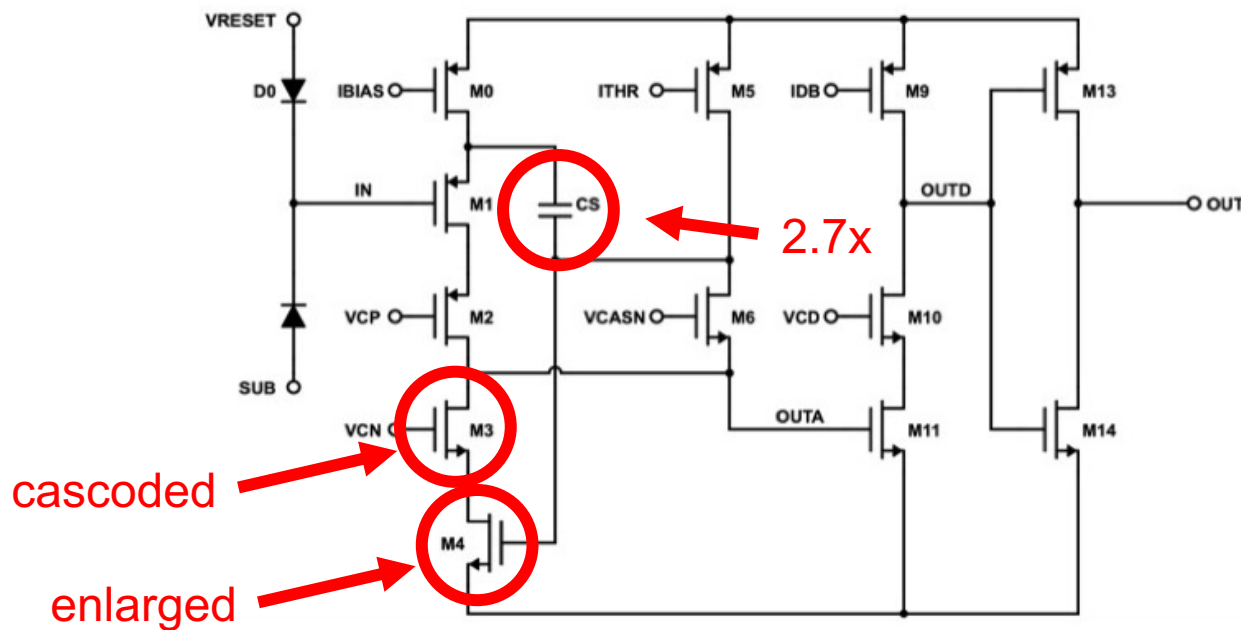
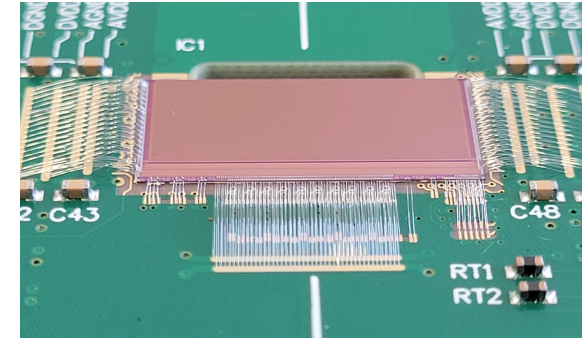


Publication submitted to JINST, preprint available at arXiv:2301.03912

MALTA2

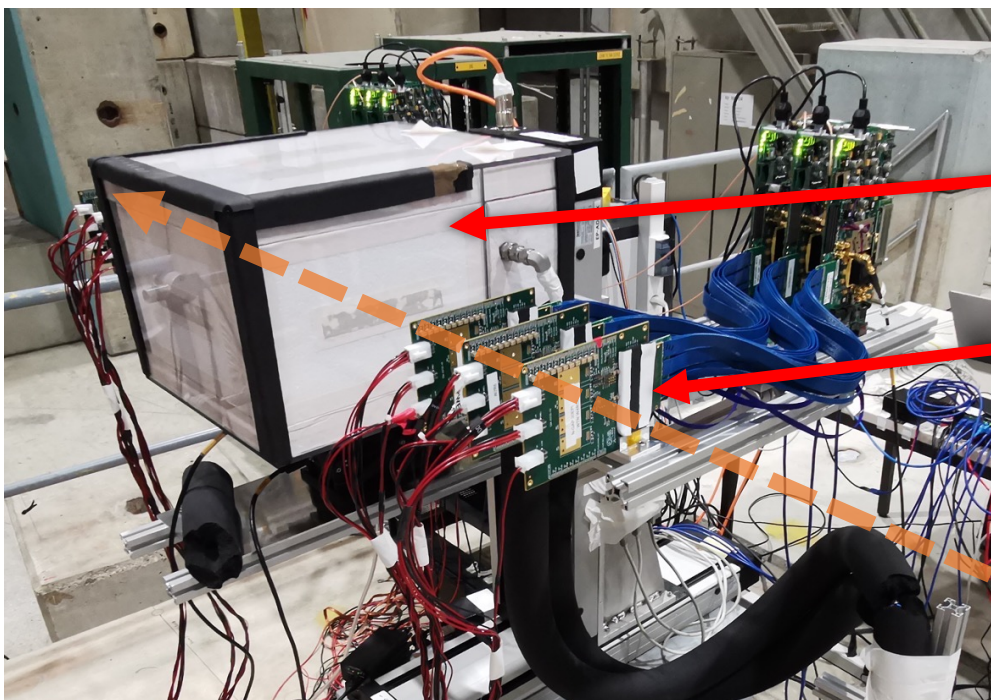
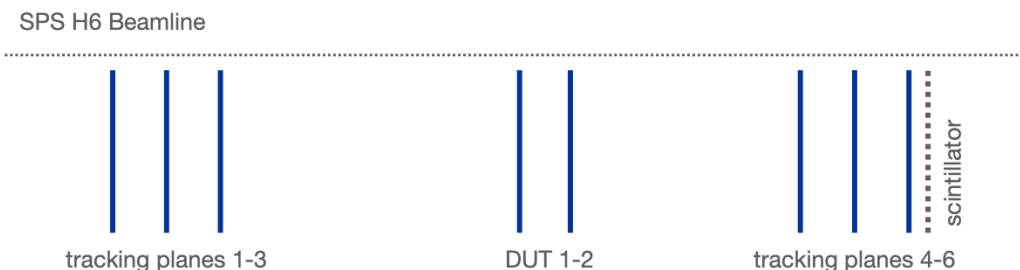
F. Piro et al, TNS, 2022, vol 69, no 6

- Features 3 flavours (Standard, NGAP, XDPW) and 2 substrates (Epi and Cz)
- Readout improvements:
 - Cascoded transistor M3 -> increases gain
 - Enlarged transistor M4 -> lower noise and higher gain
- Allows for operation at lower threshold at the order of hundreds of electrons
- Significantly **improved noise performance** compared to MALTA



MALTA-Telescope performance

- ❑ 180 GeV proton/pion beam at SPS at CERN
- ❑ Dedicated beam telescope with flexible trigger logic
 - ❑ 6 MALTA tracking planes + scintillator for timing
- ❑ **Cold box for irradiated samples**
- ❑ Allows for two independent Devices Under Test (DUTs) simultaneously

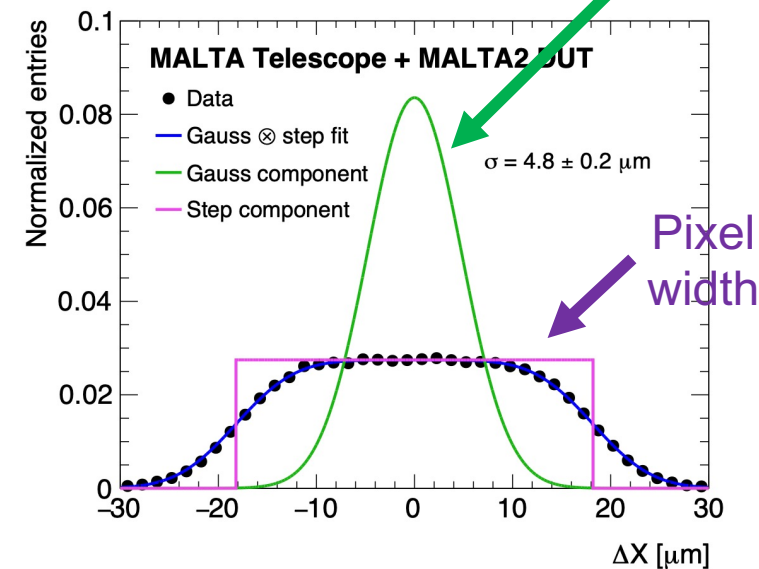


DUTs
(inside the box)

3 tracking planes
(6 in total)

Particle beam

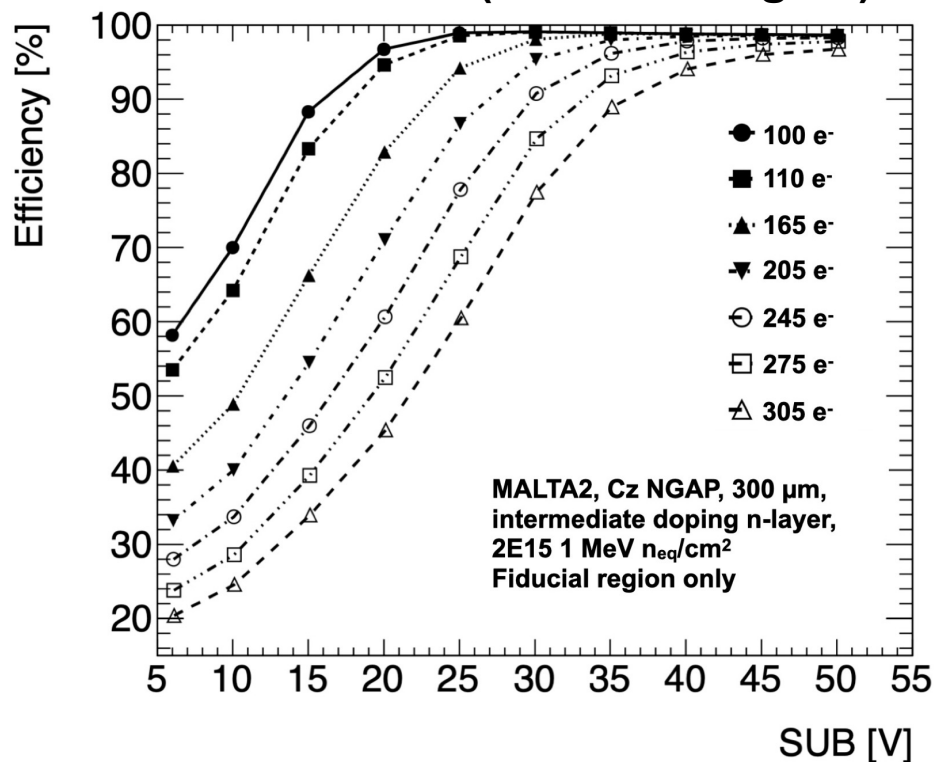
Average time resolution of 2.1 ns
Hit resolution on DUT < 5 μm



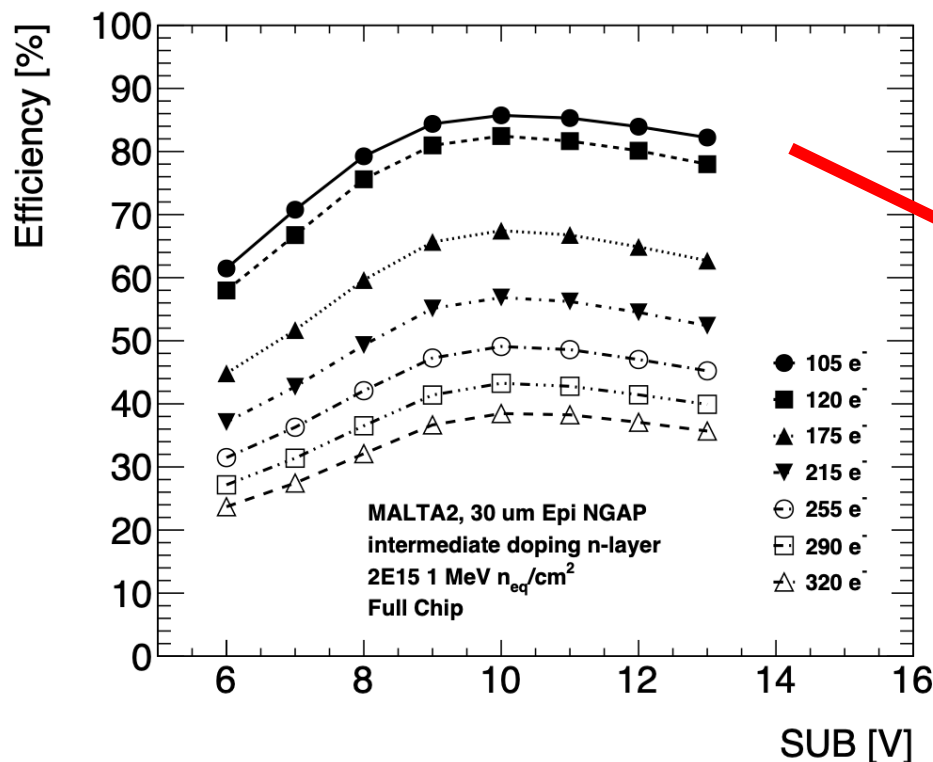
MALTA2 – neutron irradiated – Epi vs Cz

- MALTA2 Cz shows improved efficiency after irradiation compared to Epi
 - Both samples irradiated to $2E15 \text{ 1 MeV } n_{\text{eq}}\text{cm}^{-2}$

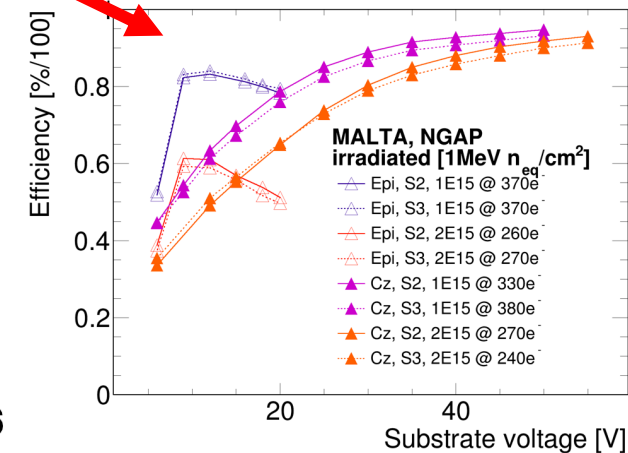
MALTA2 Cz (conductive glue)



MALTA2 Epi



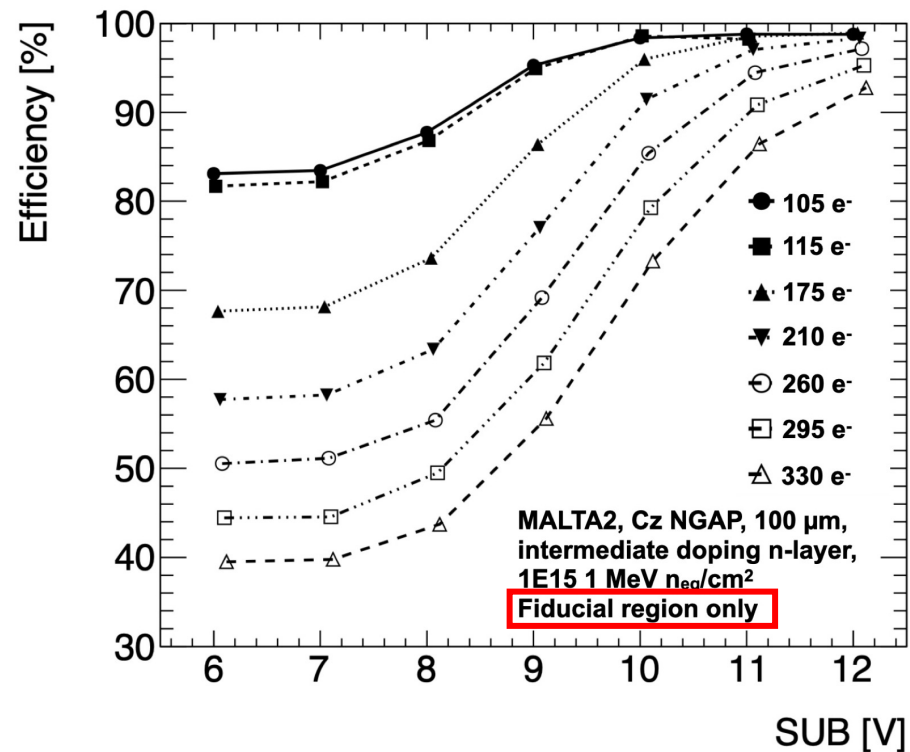
Similar trend observed for MALTA Epi and Cz



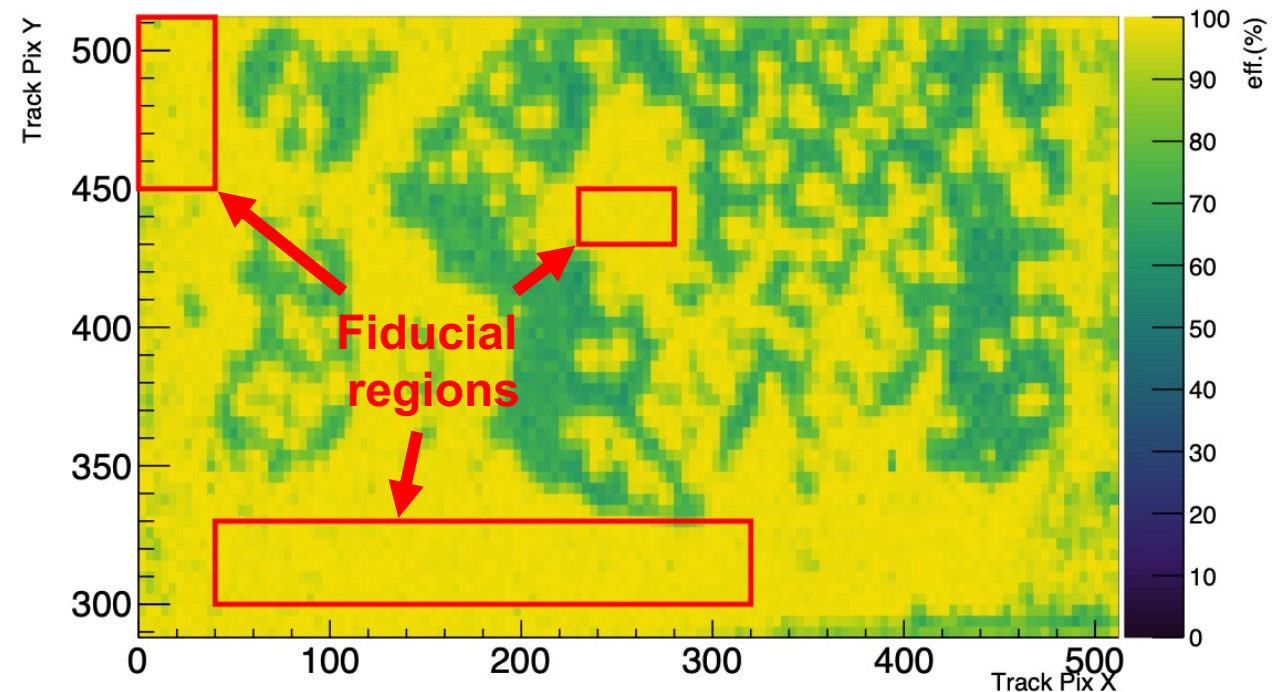
- Epitaxial sample: maximum efficiency of 86% reached at 10 V, then decreases with increasing bias

MALTA2 – neutron irradiated – conductive glue

- ❑ Contact of MALTA2 Czochralski chip with PCB crucial for efficiency
- ❑ **Conductive glue layer applied on backside** - bubble pattern emerges due to glue inhomogeneity
- ❑ Areas with good contact achieve close to 100% efficiency at high substrate bias
 - ❑ Fiducial regions account for 10.3% of the chip

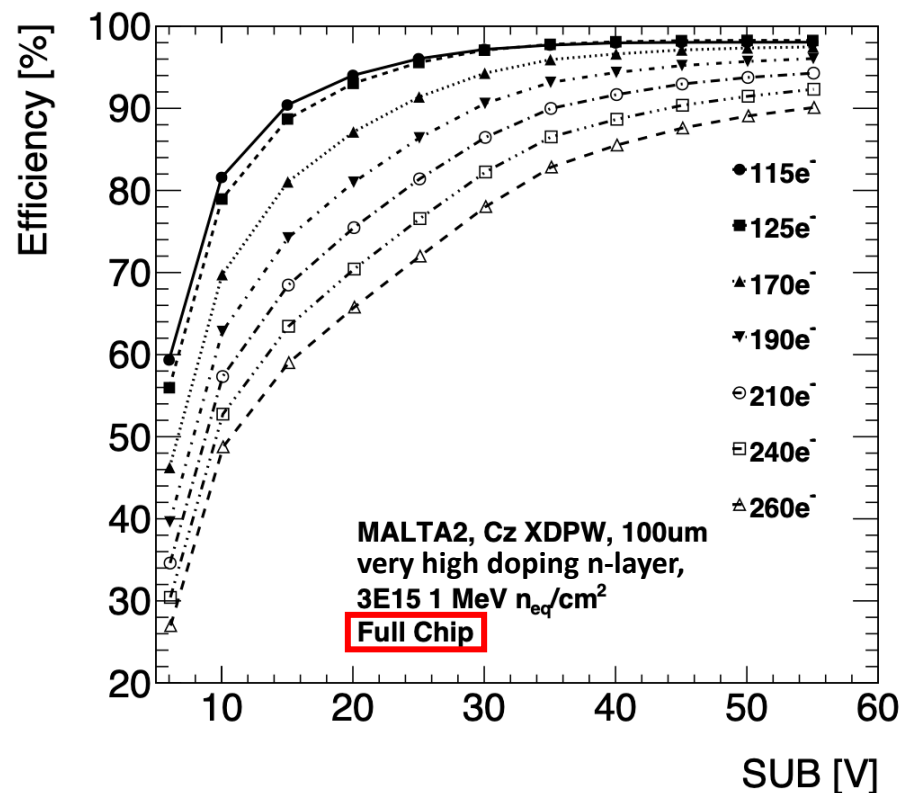


MALTA2 Czochralski – irradi. $1\text{E}15$ 1 MeV $N_{\text{eq}}/\text{cm}^2$
SUB = -12 V, threshold = 260 el.

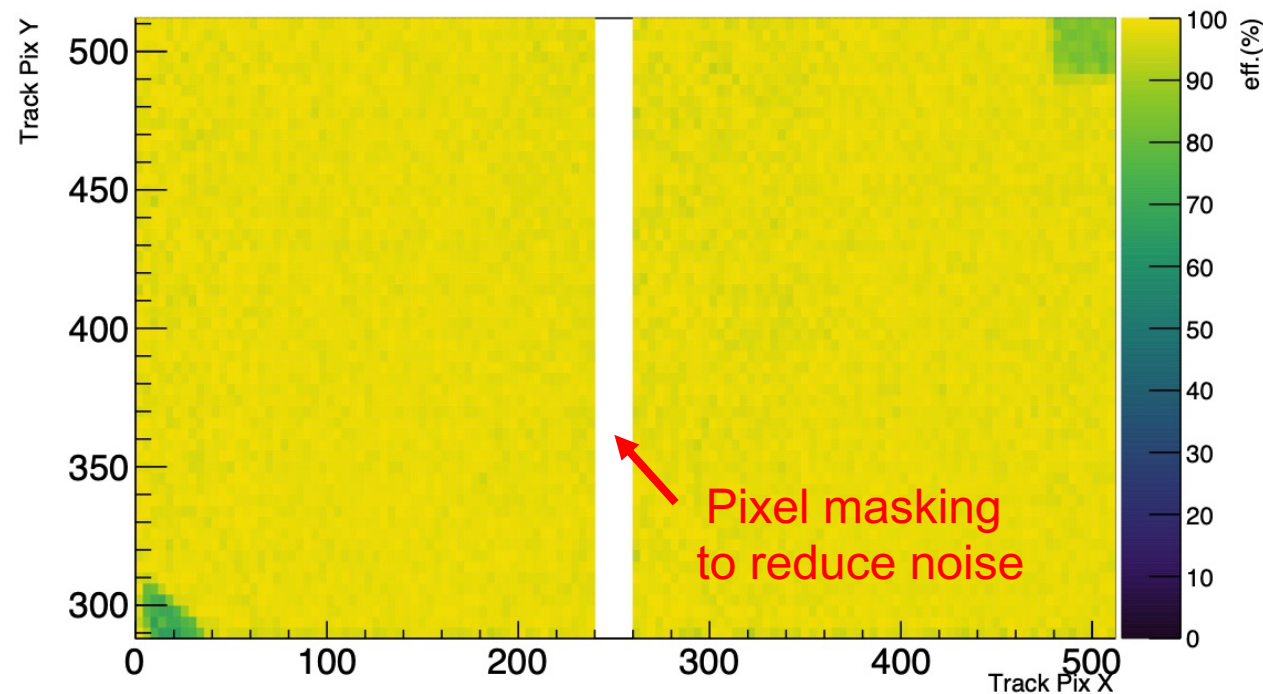


MALTA2 – neutron irradiated – back-metallisation

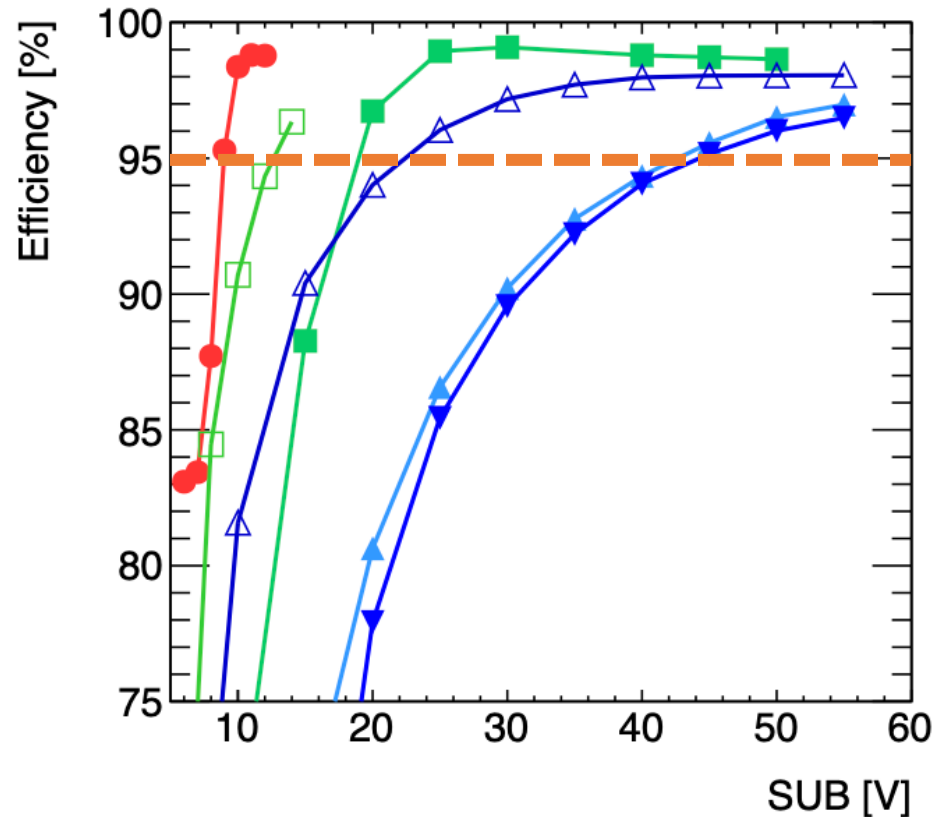
- ❑ **Back metallisation applied post-dicing** to enhance contact with the substrate
- ❑ Efficiency uniformity restored across the matrix
- ❑ Chip irradiated to $3E15 \text{ n}_{\text{eq}}\text{cm}^{-2}$ reaches efficiency above 95% at high SUB and low threshold



MALTA2 Czochralski – irradi. $3E15 \text{ 1 MeV N}_{\text{eq}}\text{cm}^{-2}$
SUB = -50 V, threshold = 115 el.



MALTA2 – neutron irradiated



MALTA2

CZ Irradiated Samples [$1 \text{ MeV } n_{\text{eq}}/\text{cm}^2$]

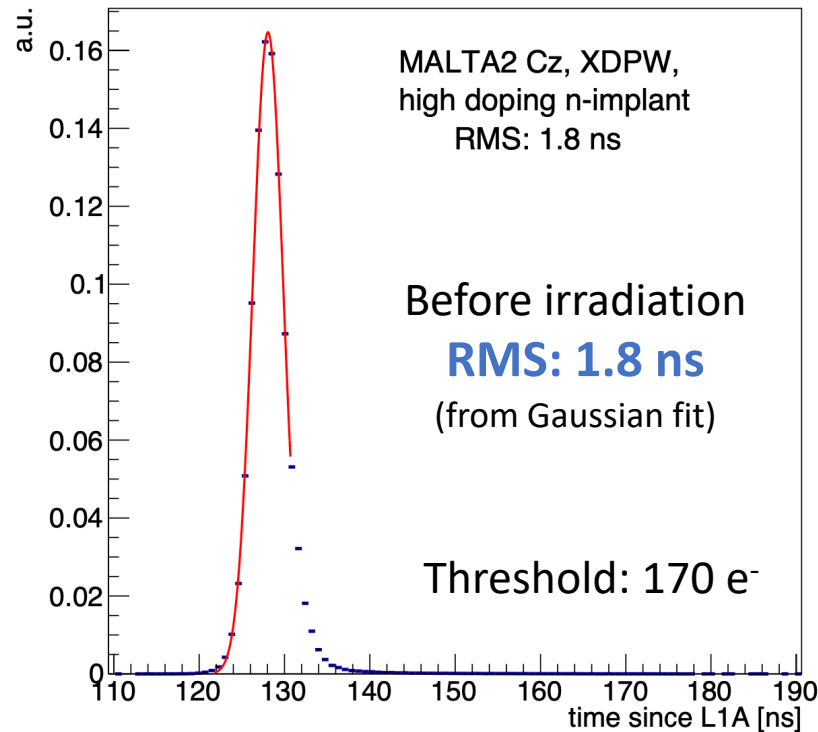
- 1E15, Fiducial Area, Conductive Glue NGAP, 100 um
- 2E15, Fiducial Area, Conductive Glue NGAP, 300 um
- 2E15, Full Chip, Backside Metallization XDPW, 100 um
- △ 3E15, Full Chip, Backside Metallization XDPW, 100 um
- ▲ 3E15, Fiducial Area, Regular Backside XDPW, 100 um
- ▼ 3E15, Fiducial Area, Regular Backside XDPW, 100 um

- MALTA2 Czochnalski efficiency >95% **up to neutron irradiation levels of $3\text{E}15 \text{ } 1 \text{ MeV } n_{\text{eq}}\text{cm}^{-2}$**
 - Sufficient substrate bias voltage needed – increases with irradiation level
 - Performance enhanced by backside metallisation

MALTA2 – neutron irradiated – timing

- ❑ Time of arrival of leading hit with respect to a scintillator reference
- ❑ Applied signal propagation correction
- ❑ NOT corrected for sampling jitter (0.9 ns) and scintillator jitter (~ 0.5 ns)

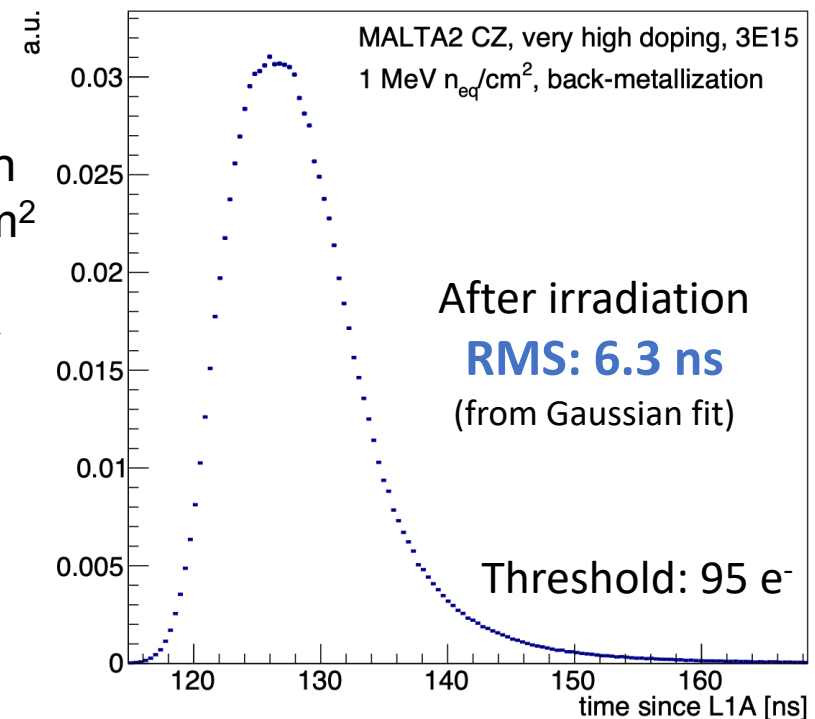
more than 98% of the clusters
are collected within 25 ns



Neutron irradiation
3E15 1 MeV n_{eq}/cm²



more than 95% of the clusters
are collected within 25 ns

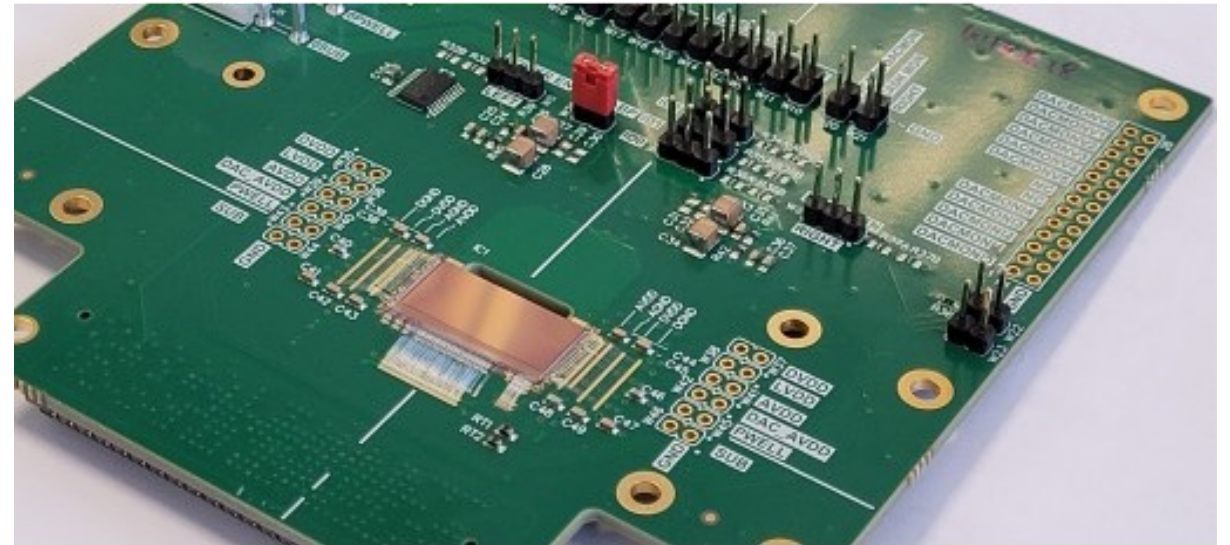


Conclusions and Future

- ❑ MALTA2 demonstrates improvements over the previous members of the MALTA family
- ❑ Chips on Czochralski substrate show **enhanced radiation hardness** compared to Epi
- ❑ Full chip **efficiency >95% after $3e15 n_{eq}/cm^2$** demonstrated with Czochralski sensors
- ❑ **Backside-metallisation** greatly improves efficiency of irradiated sensors
- ❑ Un-irradiated MALTA2 sensors with <2 ns timing resolution
 - ❑ After $3e15$ 1 MeV n_{eq}/cm^2 irradiation -> RMS 6.3 ns

MALTA3 in development

- ❑ Small demonstrator
- ❑ Data serialisation
- ❑ Improved in-pixel digital electronics
- ❑ <1 ns time-stamping in periphery
- ❑ More reliable pixel masking

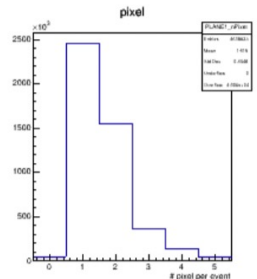
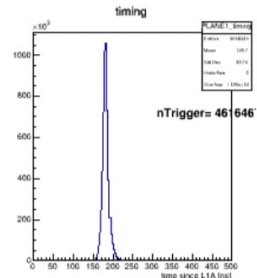
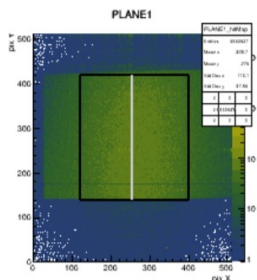


Acknowledgements

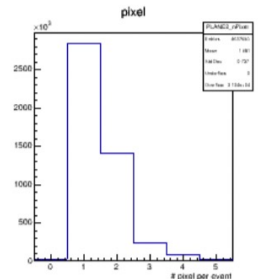
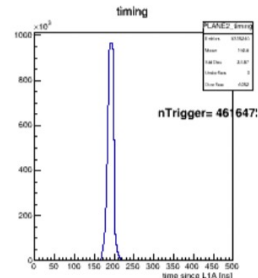
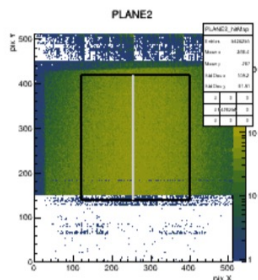
- ❑ This project has received funding from the European Union's Horizon 2020 Research and Innovation programme under grant agreement No 101004761.
- ❑ Supported by the Marie Skłodowska-Curie Innovative Training Network of the European Commission Horizon 2020 Programme under contract number 675587 (STREAM).
- ❑ This project has received funding from the European Union's Horizon 2020 Research and Innovation programme under Grant Agreement no. 654168.(IJS, Ljubljana, Slovenia)

Telescope DAQ

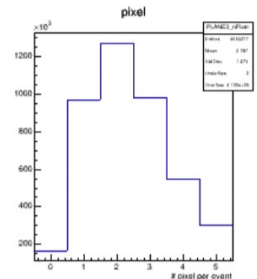
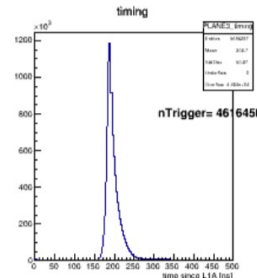
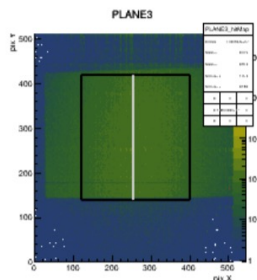
Plane 1
MALTA Epi NGAP



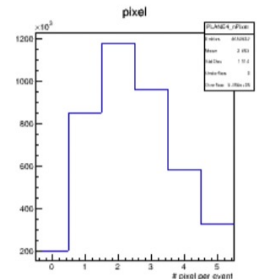
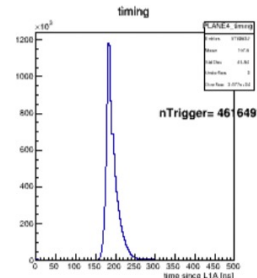
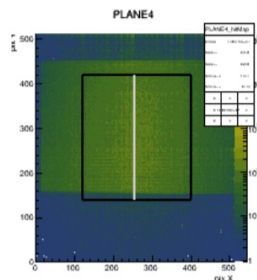
Plane 2
MALTA Cz NGAP



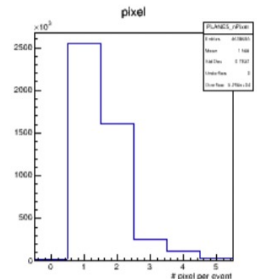
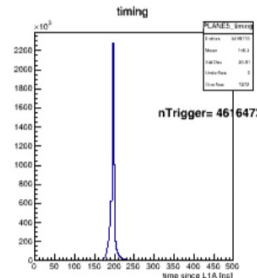
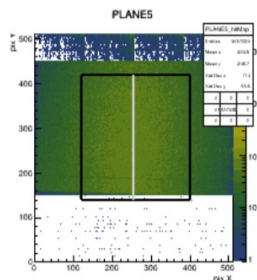
Plane 3
MALTA Cz STD



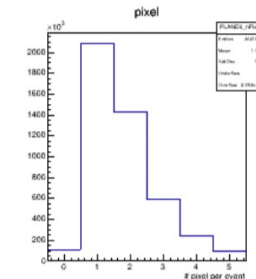
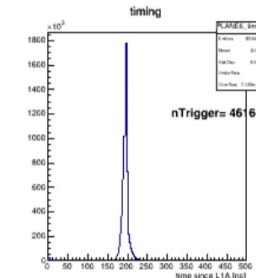
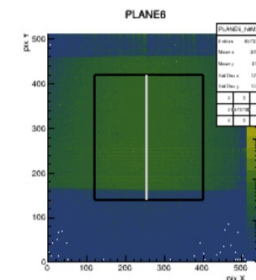
Plane 4
MALTA Cz STD



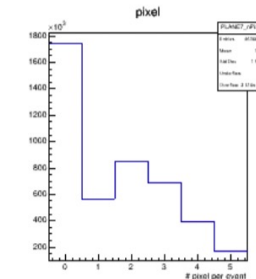
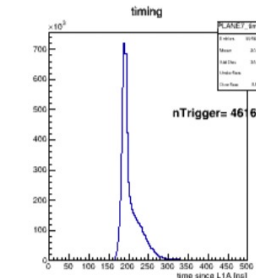
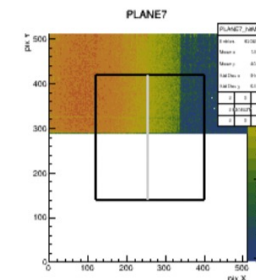
Plane 5
MALTA Cz NGAP



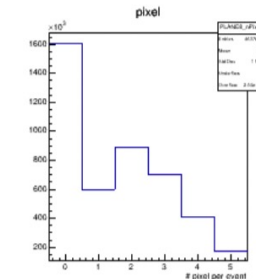
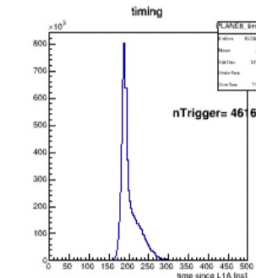
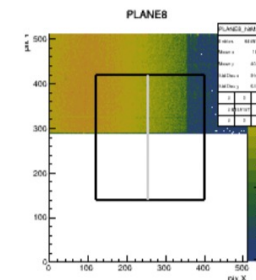
Plane 5
MALTA Epi STD



DUT1
MALTA2

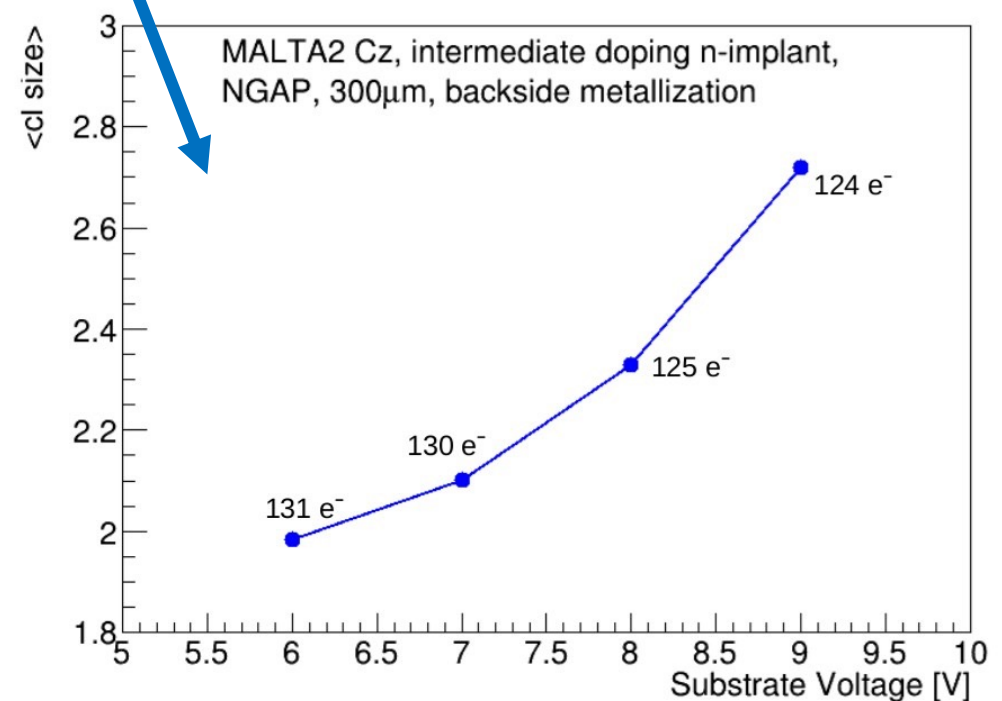
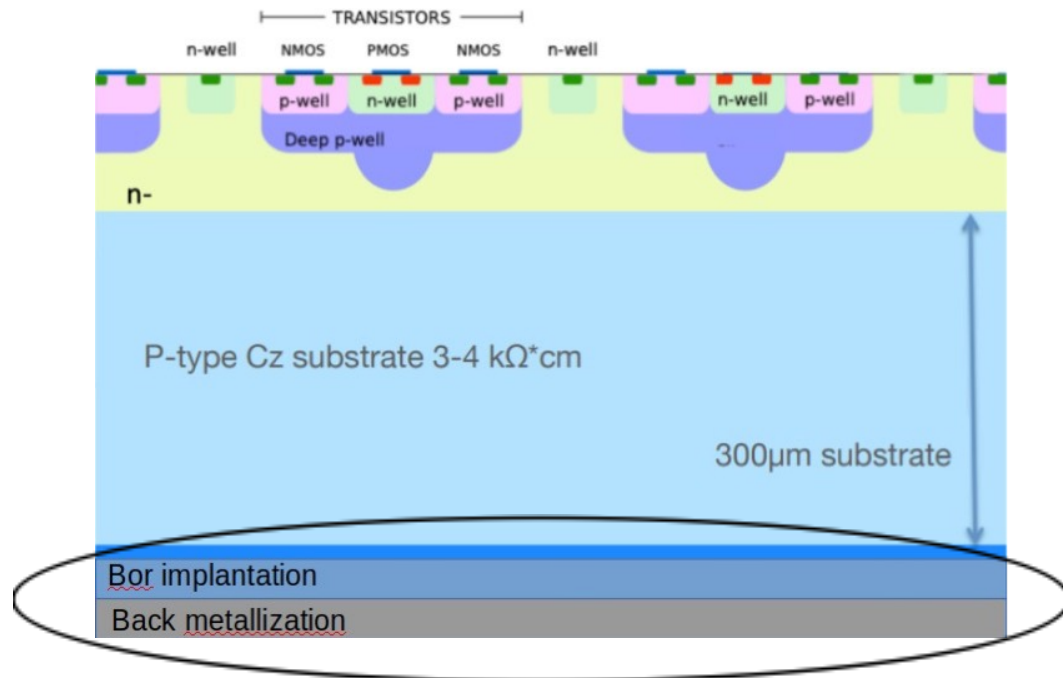


DUT2
MALTA2



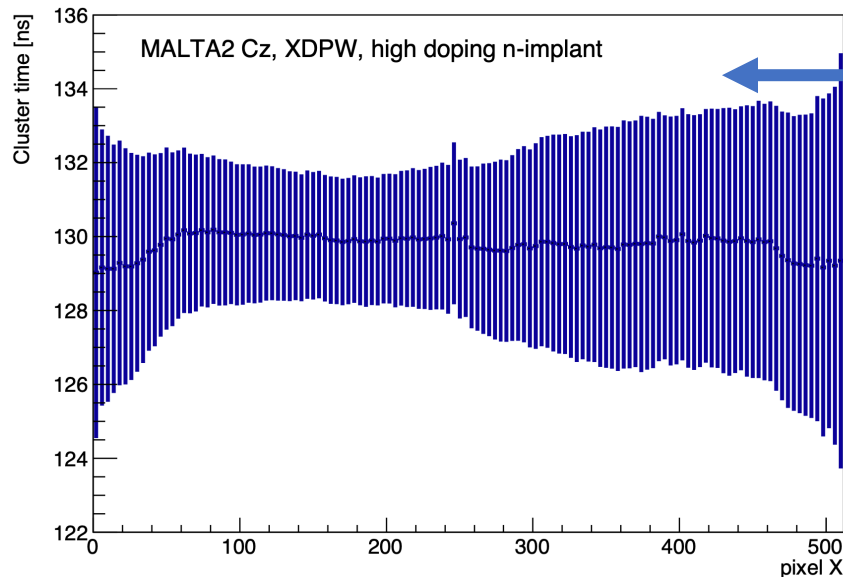
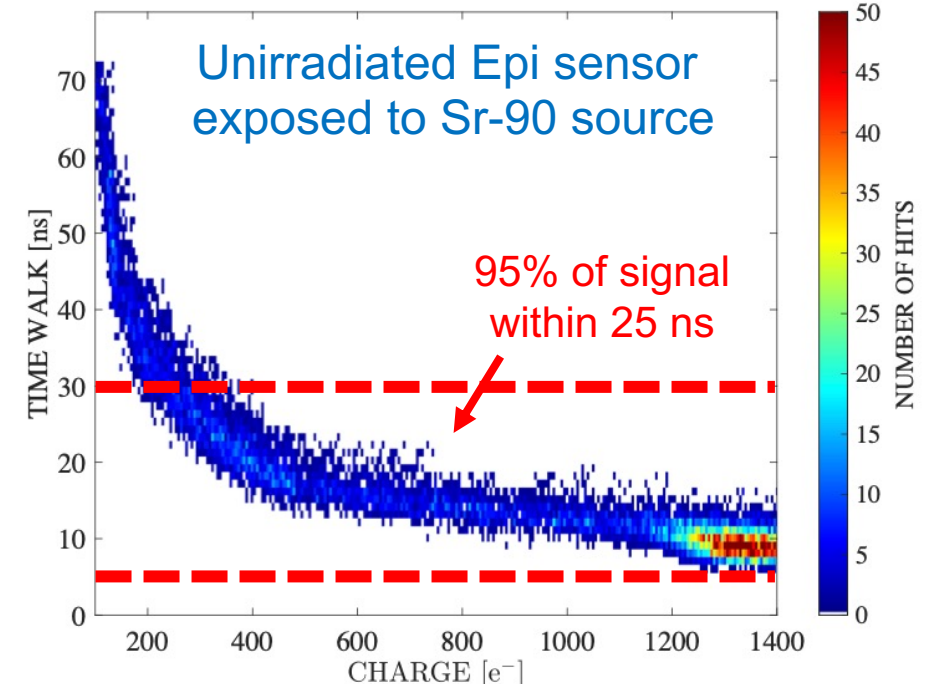
MALTA2 – back-metallisation

- Back metallisation leads to improved propagation of substrate voltage
- Back-metallised chips demonstrate **enhanced cluster size** as SUB voltage increased



MALTA2 – timing

- ❑ Time walk evaluated using pixels with analog output
 - ❑ Small signal arrives later -> from charge-sharing effects
 - ❑ Large charge signals with time-talk ~ 10 ns
- ❑ Uniformity of chip response verified both with charge injection and testbeam measurements



X correction compensates for non-uniformities in chip response

Y correction due to time propagation across the column (linear behaviour)

